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1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)

2) Limit your search by using search operators and field codes, if desired.

Example: optical (fiber fibre) ti

3) Limit the results by selecting Search Options.

4) Click Search. See [Search Examples](#)

(nitrogen* or n2*) and (oxid* or thermal-oxid*) and thickness*

Start Search

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Note: This function returns plural and suffixed forms of the keyword(s).

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